

< - (4) () >

(Photo Mask) 가 90.6%

92 3200 가 2900

90.6% 300 9.4%

Dupont Korea 2 Dupont Korea

44.8%, 47.2%

Dupont Korea Dupont 100% 9000

E-Beam 3

Blank Mask Hoya Hoya Dai Nippon

92 12 200 5%

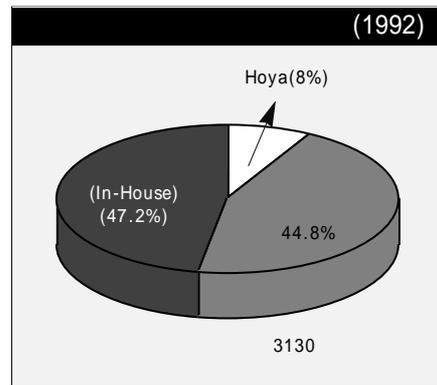
DNP, TOPPAN, HOYA, NIPPON FILCON 67%

Dupont 17%

Pattern Generator

LED Mask가

(: / , 1000)				
		1991	1992	
	9,000	7,125	14,000	- E-Beam 3
	9,000	10,600	14,750	- E-Beam 3 - Dupont 100%



Chip 가 Mask, 5~10 가

Reticle, Master Mask, Working Mask

Device Rule

가 , , , ,

가 Rule Chip Size 가 1/10 5 Reticle

1/2 .

0.5 μ m 16M DRAM 5 Reticle 0.25 μ m

. Device 0.2 μ m 0.3 μ m

0.25 μ m,

0.5 μ m가

VLSI

(: 100 , %)		
		M/S(%)
DAI NIPPON PRINTING	182	29
TOPPAN PRINTING	169	27
(INC. PRINTRONICS)		
DU PONT PHOTOMASKS	109	17
HOYA	55	9
PHOTRONICS	42	7
ALIGN-RITE	19	3
COMPUGRAPHICS(UK)	10	2
NIPPON FILCON	10	2

(: 100)										
	1988	1989	1990	1991	1992	1993	1994	1995	1996	1997
	-	-	-	18	29	42	49	63	73	87
	15.3	18	21.2	6	3	5	6	7	7	8
	15.3	18	21.2	24	32	47	55	70	80	95
	-	-	-	-	-	-	-	-	-	-
	15.3	18	21.2	4	32	47	55	70	80	15
(%)	-	-	-	75	90.6	89.4	89	90	91.2	91.6

) 1991

SiCl4, H2, O2

90%

Stepper Reticle

Cr, Ta,

Si 가

Device 1M DRAM 15 , 4M DRAM 21 , 16M

DRAM 27 가 Chip Stepper

Working Mask 가

가

가 Memory Asic None Memory

93

5 가 Phase Shift Mask가

Phase Shift Mask , Phase Shift

가

Blank Mask SiO2()가

Business Fluctuation

가

(: 100)					
	1992	1993	1994	1995	1996
	20	30	32	37	41
	40	60	64	68	72
	5	7	9	10	11
/	5	7	10	15	17
	80	104	115	125	141

Photo Resist (: M/T, %)					
	1992	1993	1994	1995	1996
	270	300	357	373	400
	80	100	150	180	210
	190	200	207	193	190
	30	39	42	48	53

Device
Phase
Shift Mask 가
Pellicle

Dupont Korea
Stepper, LCD, Aligner 2000
320 192 60.0%
Dupont Korea 78 24.4%, 50 15.6%
Dupont Korea
IC 가 가 Photo Lithography
Mitsui, Asahi 가
1 400 6000 57.8%
3000 28.8%, 700 6.7%

	(: M/T, 100)				
	1992	1993	1994	1995	1996
Broad Band	175	160	150	140	130
g Resist	100	115	120	130	140
i Resist	15	35	48	57	70
Deep-UV & E-Beam	0.2	1	4	6	10
Flat Panel Display	10	20	35	40	50
	300	331	357	373	400
	47	53	61	70	80

	Photo Resist (: 100, K Gallons)			
	1991	1992	1993	1994
Positive	174 (570)	185 (604)	203 (658)	220 (737)
Negative	50 (476)	43 (457)	46 (438)	44 (419)
Advanced	24	30	35	41
	248	263	284	305

Particle Chip
BB(Broad Band)type, LR(Low - Reflect-ance)type, AR(Anti-Refletive)type
BB type PR (350nm ~ 450nm) Aligner 92%
LR AR type Stepper g-line(436nm) & i-line(365nm)
99%
, 0.5µm ULSI Design Rule (365nm ~ 436nm)
가 Excimer Laser(248nm) Stepper
Excimer Laser 64M, 2~3 Excimer Laser
LCD 가 Particle Control

LCD
가

line Stepper Excimer , R&D i-

(Photo Resist) 가
92 P/R 300 가 100 33%
P/R g-line(1 μ m) 170 Shipley가 85 35%, Tokyo
Oka 25 15%
Sub-micron g-line 100 82 82% Tokyo Oka Hoechst
가 18 18%
i-line 15 Tokyo Oka 9 60%, JSR 4.5 30%, Sumitomo 1.5 10%
, Flat Panel Display 15 Hoechst 11.3 75%, Shipley 2.2 15%, Tokyo
Oka 1.5 10%
P/R Hoechst
Tokyo Oka, Shipley
가

1M P/R
P/R 92 2 5800 , P/R 가 Positive 1 8500 ,
71.7% , Tokyo Oka가 Shipley, Hoechst

DRAM Process	Photo Resist			
	1M DRAM	4M DRAM	16M DRAM	64M DRAM
Photo Resist	g	g, i	i	D-UV()

Photo Resist							
1987	1988	1989	1990	1991	1992	1993	1994
110	146	177	196	208	240	274	298

P/R 2 가 , Resist 가 Negative Positive
Negative PVA,
가
가
가 , pH, , , , , ,
가 가 가

가

가

(가)

가

가

Lithography

가

g , i , Deep UV, Eximer Laser

Device Rule Pattern Lithography

Process Process Margin 2

Lithography

i g Positive Negative

0.35 ~ 0.4Mm

Stepper Process

i Lithography g i

Naphtaguinon Novolac i Lithography

i

Know-How

가 Balast Benzene

Control

1M 4M DRAM

4M DRAM 가 Broad Band Design Rule g

Step 1 i 가 2 i 가 가

16M DRAM

64M DRAM Phase Shift Mask Positive Deep UV Resist가

2 i

3 i Phase Shift Mask Positive Deep UV Resist 64M

Negative i

DRAM

Positive D-UV Resist

가

가 , 256M DRAM

0.3 μ m 가 Pattern

가
Desire Process
256M DRAM
가
()

94

Desire Process

X-

X-

SPEC

가

가

가
High Resolution

가

High Grade
High Resolution

가
가

< 1994/2/1 >